

Angle Resolved PhotoEmission Spectroscopy (ARPES) Study of  $Sr_4Ru_3O_{10}$  single crystals and Intrinsic  $Bi_2Te_3$  Topological Insulator Thin Films

# **Prosper Ngabonziza**

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### Acknowledgement



**Beamline CASSIOPÉE** 



**Bryan P. Doyle** 

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#### **Motivation**

- Understanding the electronic structure of materials:
  - Near Fermi level Insights into the solid-state for the materials under investigation
- Interesting properties of solids are determined by electrons near Fermi level:
  - conductivity,
  - magnetoresistance,
  - superconductivity,
  - Magnetism

New material with rich Physics and Novel future technological applications:

- Transition Metal Oxides :
  - Oxide Electronics
- Topological Insulators :
  - Spintronic and quantum computation

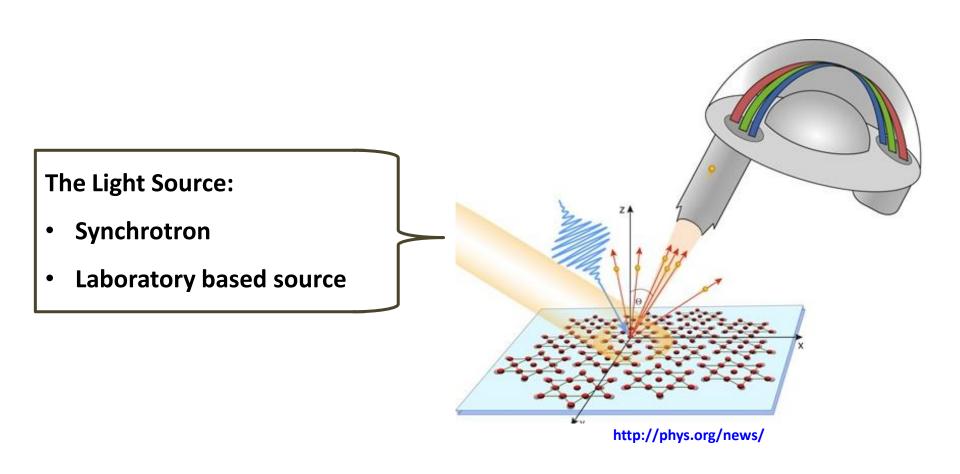
Materials Innovation for Leading Device Revolution



http://www.mrs.org/fall-2014-plenary/

### **Motivation**

➤ ARPES: surface sensitive tool to look into the narrow energy slice around Fermi level



# **Outline**

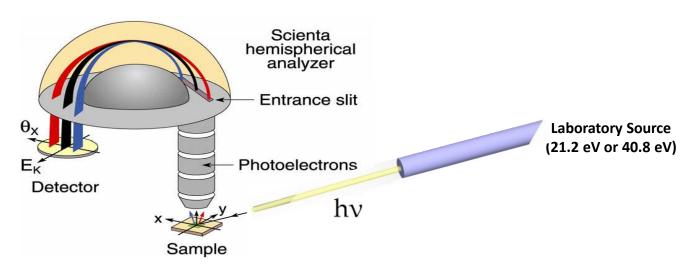
u introducing angle resolved photoemission spectroscopy (ARPES)	
☐ ARPES Study on Sr <sub>4</sub> Ru <sub>3</sub> O <sub>10</sub> Single Crystals with Synchrotron Light Source	

☐ ARPES Study on Intrinsic Bi<sub>2</sub>Te<sub>3</sub> Topological Insulator Thin Films with Lab Light Source

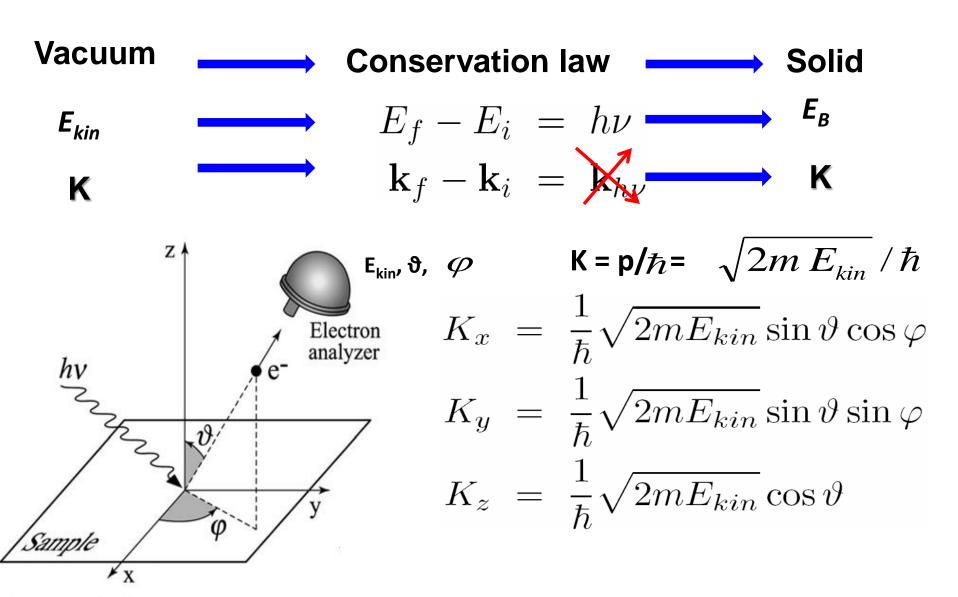
# Introducing angle resolved photoemission spectroscopy (ARPES) A. Experimental Considerations

#### In an ARPES experiment:

- 1. Incoming beam of monochromatic light (U.V or S.X.R) illuminates an atomically flat sample;
- 2. Due to the photoelectric effect, the sample emits electrons;
- 3. The kinetic energy and momentum of these electrons are measured by use of an appropriate instrument;
- 4. The data measured reflect the electronic properties of the material;
- 5. Thus, ARPES measures electronic excitations in solid → band structure.



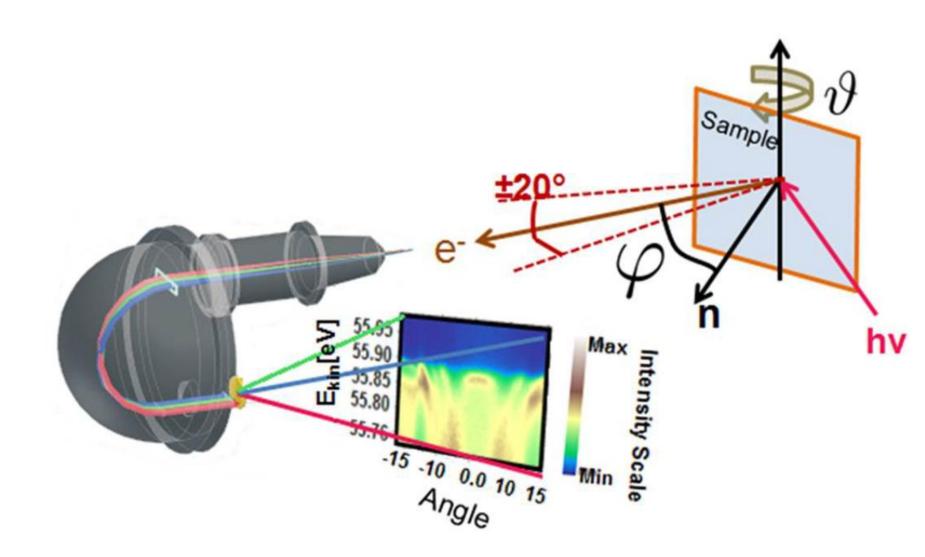
# Introducing angle resolved photoemission spectroscopy (ARPES) B. Theoretical Considerations



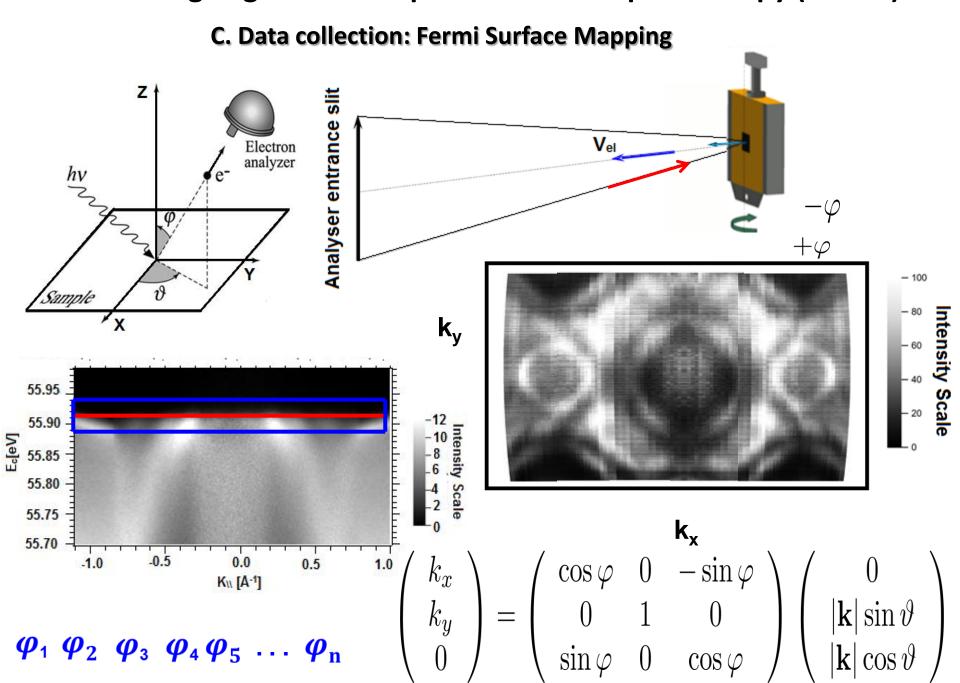
A. Damascelli., Physica Scripta T109, 61 (2004)

**Introducing angle resolved photoemission spectroscopy (ARPES)** 

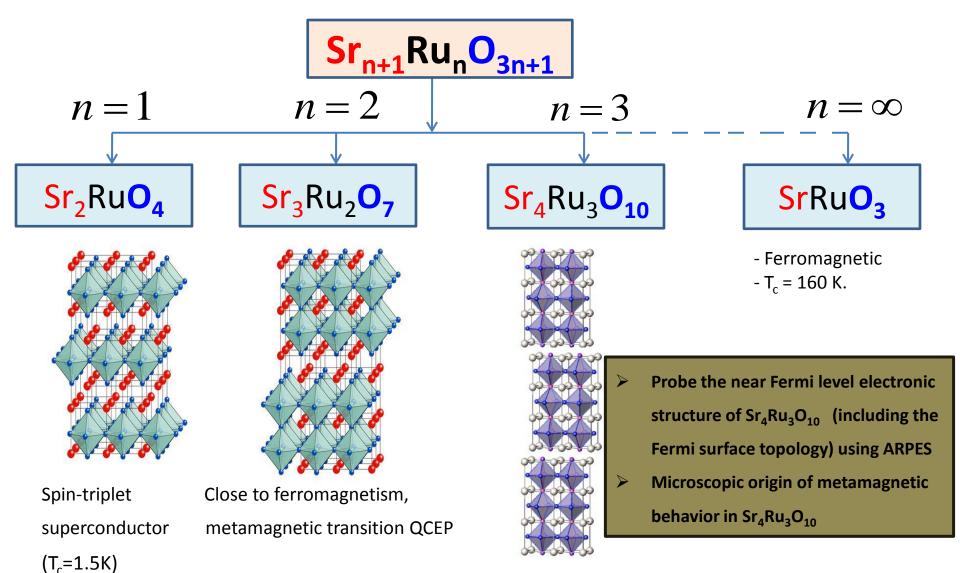
# C. Data collection: From Energy Analyzer to 2D maps



# Introducing angle resolved photoemission spectroscopy (ARPES)



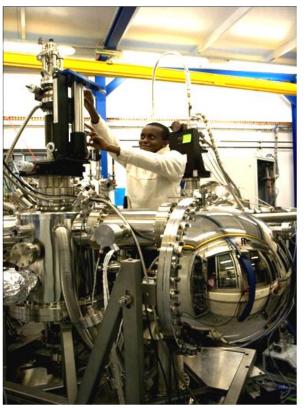
# General Introduction to $Sr_{n+1}Ru_nO_{3n+1}$



## **ARPES Experiment at Soleil**



#### **Beamline CASSIOPÉE**

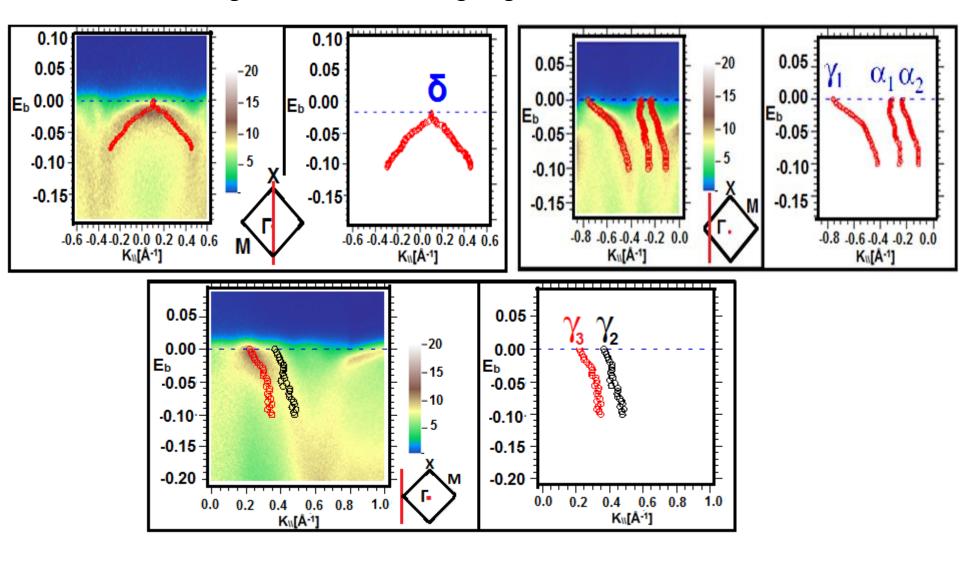




- $\square$  Single crystals of  $Sr_4Ru_3O_{10}$  cleaved in situ at the measurement temperature of 5 K;
- $\Box$  kept in ultra-high vacuum conditions (~ 5x10<sup>-10</sup> mbar) to avoid surface contamination;

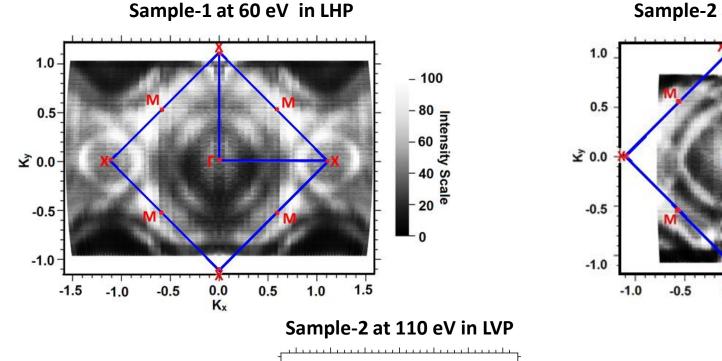
Results: E<sub>f</sub> crossing

☐ Six bands crossing the Fermi level, then giving rise to six Fermi Surface Sheets



P. Ngabonziza et al., Proceeding of the SA Institute of Physics (2012)

**Results: Fermi Surface Mapping High Symmetry Points in the BZ** 



Sample-2 at 60 eV in LHP

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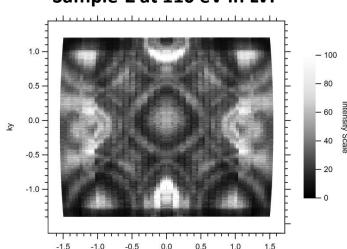
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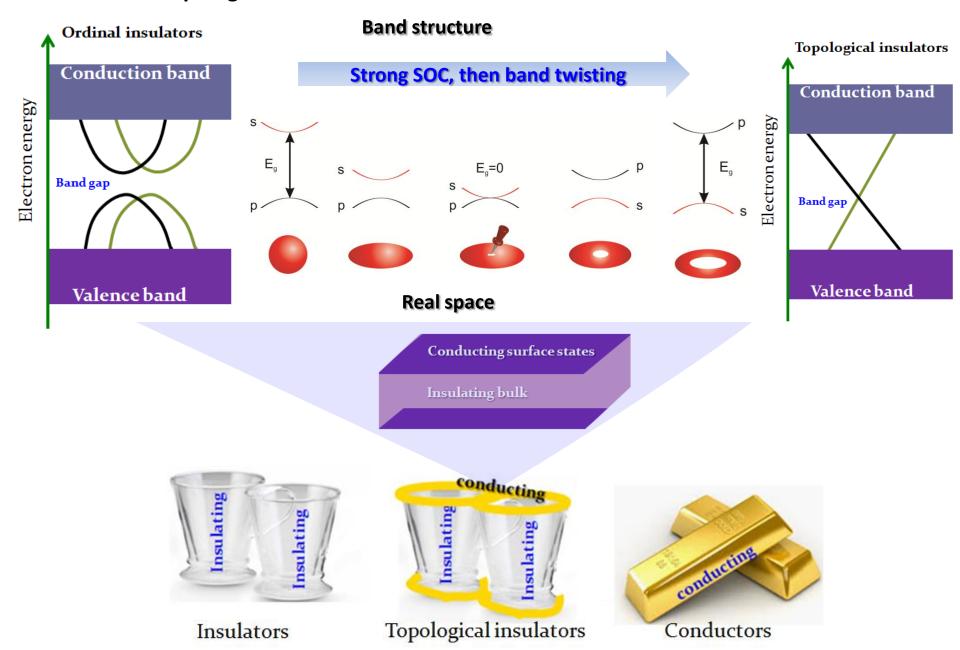
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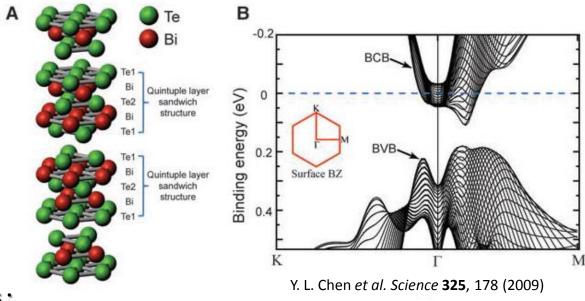
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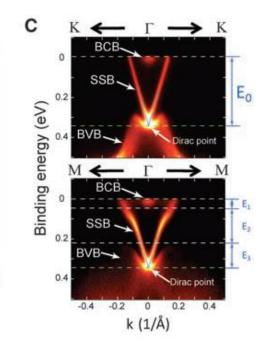


#### > Normal and topological insulators



Current challenges in the field: Bulk single crystals vs Thin films





#### <u>lssues</u>:

- Bulk conduction:
  - ☐ Complicate direct observation of surface effects
- Doping/counter-doping
  - Defects introduction
  - Low surface mobility

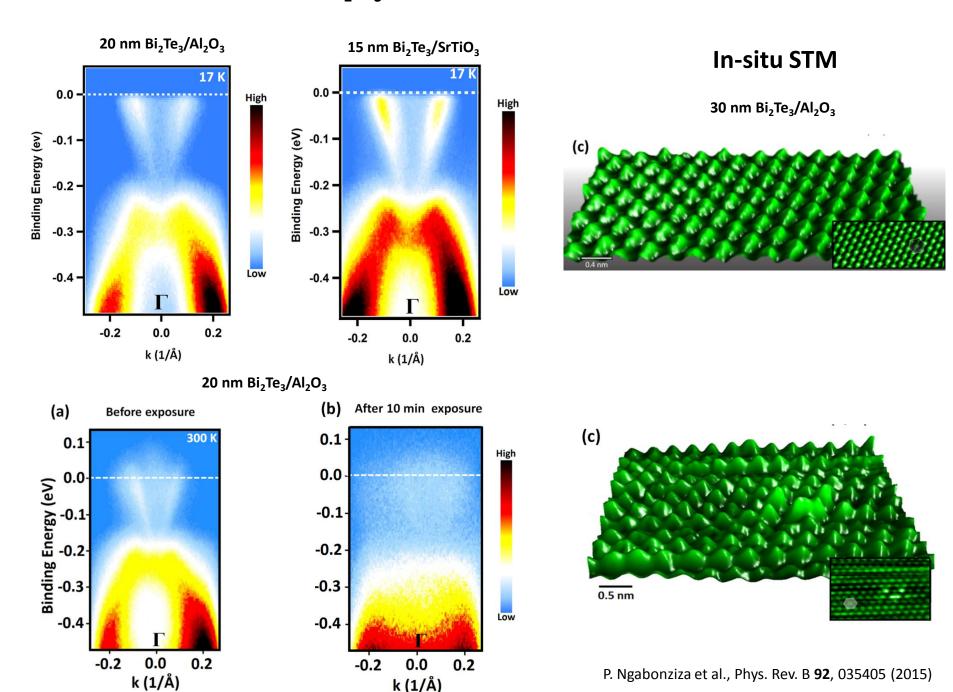
- ✓ Thin films:
  - Bulk insulating thin films (ARPES),
  - In-situ Capping,
  - Top and bottom gate,
  - Normal state transport (HBs) and JJs

- M. Veldhorst et al., Nat. Mater. 11, 417 (2012)
- M. Snelder et al., Supercond. Sci. Technol. 27, 104001 (2014)

Combined system for growth and in-situ characterizations



**UHV** conditions



**Summary** 

